## Notice of References Cited Application/Control No. | Applicant(s)/Patent Under Reexamination HSIEH, WENHAO | Examiner | Art Unit | Page 1 of 1

## U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-6,313,849	11-2001	Takase et al.	345/684
	В	US-6,384,845	05-2002	Takaike, Shinichi	345/786
	C	US-			
	D	US-			
	Е	US-			
	F	US-		·	
	G	US-			
	Н	US-			-
	-	US-			
	J	US-			
	к	US-	*		
	L	US-			
•	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	<b>p</b>					
	œ					
	R					
	S					
	Τ					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	w	·
	x	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.